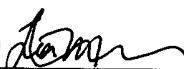


# **Notice of References Cited**

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Reexamination  
NISHITA, NAOKI

Examiner  
Tina M Lin



Art Unit  
2874

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## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0102073 a1	08-2002	SHIRAKAWA, TSUGUHITO	385/92
	B	US-2002/0197023 a1	12-2002	Serizawa, Naoshi	385/88
	C	US-5,923,805	07-1999	Anderson et al.	385/86
	D	US-6,450,703 b1	09-2002	Shirakawa, Tsuguhito	385/92
	E	US-6,459,835 b1	10-2002	Nagaoka et al.	385/43
	F	US-6,287,016 b1	09-2001	Weigel, Hans-Dieter	385/58
	G	US-6,371,663	04-2002	Kneier et al.	385/88
	H	US-5,631,990	05-1997	Hashizume, Hideki	385/92
	I	US-5,973,862	10-1999	Hashizume, Hideki	359/819
	J	US-6,247,851 b1	06-2001	Ichihara, Jun	385/56
	K	US-			
	L	US-			
	M	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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